Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10593764	LIU ET AL.
Examiner	Art Unit
JULIO PEREZ	2617

	SEARCHED				
Class	Subclass	Date	Examiner		
455	405	3/19/2010	JP		
	406	3/19/2010	JP		
	407	3/19/2010	JP		
	408	3/19/2010	JP		
379	114.2	3/19/2010	JP		

SEARCH NOTES		
Search Notes	Date	Examiner
East (text search)	3/18/2010	JP
consulted Binh K. Tieu (455/406)	3/18/2010	JP
Inventor's search	3/18/2010	JP

Subclass	Date	Examine
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